

Comparison of acceleration soft-error tests using white neutron beam and quasi-monoenergetic neutron beam

S. Yamamoto,^a K. Kokuryou,^b H. Sugimoto,^c J. Mitsuhashi,^a N. Matsuoka,^d and Y. Nagai^d

^a *Renesas Technology Corporation, Mizuhara, Itami, Hyogo 664-8641, Japan*

^b *Tada electric Corporation, Higashitada, Kawanishi, Hyogo 666-0122, Japan*

^c *Renesas Semiconductor Engineering Corporation., Mizuhara, Itami, Hyogo 664-8641, Japan*

^d *Research Center for Nuclear Physics (RCNP), Ibaraki, Osaka 567-0047, Japan*

Neutron-induced soft error is a serious reliability issue for semiconductor devices [1-2]. It is therefore important to accurately predict neutron-induced soft-error rate (SER). There are two acceleration test methods for the estimation of neutron-induced soft-error rate [3]: an irradiation test using a white neutron beam, and an irradiation test using a quasi-monoenergetic neutron beam. We investigated the difference between both test methods using white and quasi-monoenergetic neutron beams at the Research Center for Nuclear Physics of Osaka University.

We used 0.15 μ m SRAM in the acceleration test. The test boards mounted with 0.15 μ m SRAM were set up along the beam line. Before beam irradiation, an all-zero data pattern was written from the external controller. Failed addresses were stored in the external controller after beam irradiation. For the quasi-monoenergetic neutron beam, the energies used were 14, 26, 62, 98, 148, 198 and 392MeV and neutrons were produced by a $^7\text{Li}(p,n)^7\text{Be}$ reaction. Figure 1 shows the quasi-monoenergetic neutron beam energy spectrums obtained using a liquid scintillator. Each neutron energy spectrum has a high-energy peak and a low-energy tail. Low-energy-tail correction is essential for the accurate estimation of SER cross section in the quasi-monoenergetic neutron beam test. We performed the low-energy-tail correction using the iterative folding procedure described in ref.4. Figure 2 shows the nominal energy distribution at sea level [3] and the white-neutron-beam energy distribution of RCNP using the nuclear reaction between a Pb target and a 392MeV proton. The energy distribution of RCNP is very similar to the nominal energy distribution, but has a higher intensity.

Figure 3 shows SEU cross sections as a function of neutron energy E_n in 0.15 μ m SPRAM. SEU cross section rises rapidly and almost saturates at more than 60MeV. In the quasi-monoenergetic neutron beam irradiation test, SER was calculated using

$$\text{SER} = \int c(E_n) \cdot F(E_n) dE, \quad (1)$$

where $c(E_n)$ is the SEU cross section corrected for the contribution obtained from neutrons in the low-energy neutron tail and $F(E_n)$ is the differential neutron flux, which is as a function of E_n .

In the white-neutron beam irradiation test, we calculated the SER of 0.15 μ m SPRAM on basis of JEDEC STD [3]. Figure 4 shows the estimated SERs obtained in both acceleration tests. The SER of the

white neutron beam is in good agreement with that of the quasi-monoenergetic neutron beam.

We performed two SER acceleration tests with a quasi-monoenergetic neutron beam and a white neutron beam using 0.15 μ m SRAM. SER can be predicted accurately using the white neutron beam, as in the case using the quasi-monoenergetic neutron beam.

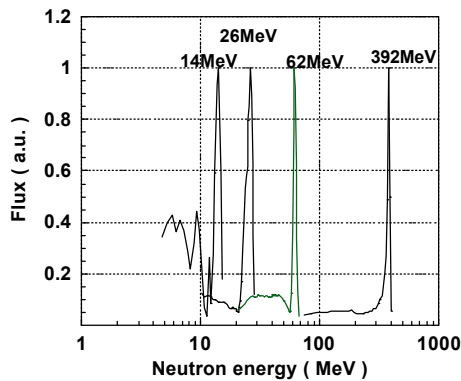


Figure 1. The quasi-monoenergetic neutron beam energy spectrums

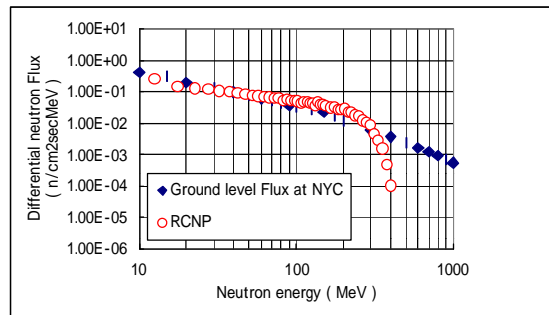


Figure 2. The white neutron beam energy distribution

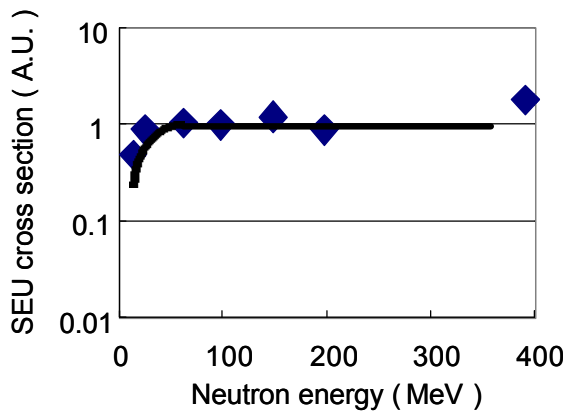


Figure 3. The neutron energy dependence of SEU cross section of 0.15 μ m SRAM

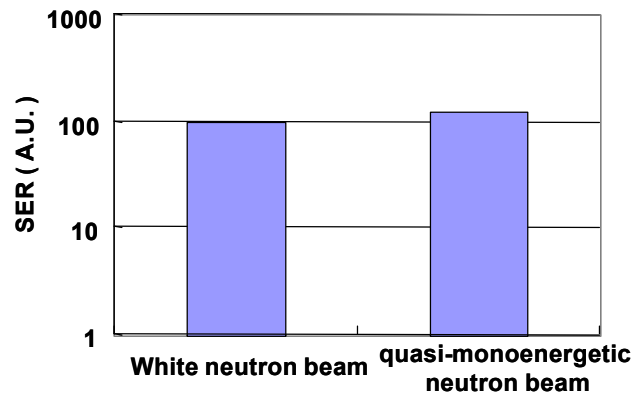


Figure 4. comparison of SER from white and quasi-monoenergetic neutron beam

References

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